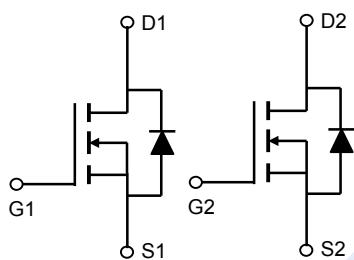
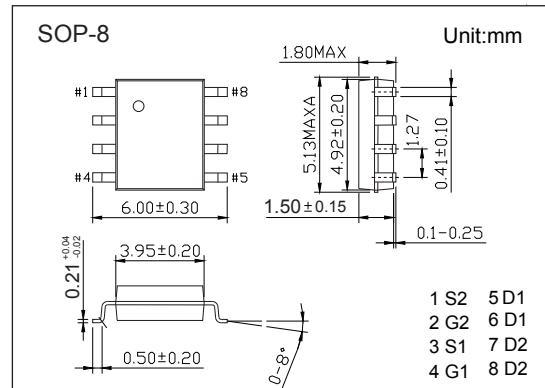


Dual N-Channel MOSFET

AO4852 (KO4852)

■ Features

- $V_{DS} (V) = 60V$
- $I_D = 3.5A$ ($V_{GS} = 10V$)
- $R_{DS(ON)} < 90m\Omega$ ($V_{GS} = 10V$)
- $R_{DS(ON)} < 105m\Omega$ ($V_{GS} = 4.5V$)



■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	10 Sec	Steady State	Unit	
Drain-Source Voltage	V_{DS}	60	± 20	V	
Gate-Source Voltage	V_{GS}				
Continuous Drain Current	I_D	3.5	3	A	
		2.8	2.4		
Pulsed Drain Current	I_{DM}	20	8	mJ	
Avalanche Current	I_{AR}				
Repetitive Avalanche Energy	E_{AR}	9.6	1.4	W	
Power Dissipation	P_D				
	2	0.9			
Thermal Resistance.Junction- to-Ambient	R_{thJA}	62.5	90	$^\circ C/W$	
Thermal Resistance.Junction- to-Lead	R_{thJL}	150	40	$^\circ C$	
Junction Temperature	T_J				
Storage Temperature Range	T_{stg}	-55 to 150			

Dual N-Channel MOSFET

AO4852 (KO4852)

■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V_{DSS}	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	60			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$			1	μA
		$V_{DS}=60\text{V}, V_{GS}=0\text{V}, T_J=55^\circ\text{C}$			5	
Gate-Body Leakage Current	I_{GSS}	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.7		2.6	V
Static Drain-Source On-Resistance	$R_{DS(\text{on})}$	$V_{GS}=10\text{V}, I_D=3\text{A}$			90	$\text{m}\Omega$
		$V_{GS}=10\text{V}, I_D=3\text{A}, T_J=125^\circ\text{C}$			159	
		$V_{GS}=4.5\text{V}, I_D=2\text{A}$			105	
On State Drain Current	$I_{D(\text{ON})}$	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	20			A
Forward Transconductance	g_{FS}	$V_{DS}=5\text{V}, I_D=3\text{A}$		15		S
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$		372	450	pF
Output Capacitance	C_{oss}			31		
Reverse Transfer Capacitance	C_{rss}			17		
Gate Resistance	R_g	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.7	2.6	Ω
Total Gate Charge (10V)	Q_g	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=3\text{A}$		7.1	9.2	nC
Total Gate Charge (4.5V)				3.6		
Gate Source Charge	Q_{gs}			1		
Gate Drain Charge	Q_{gd}			2		
Turn-On DelayTime	$t_{d(\text{on})}$	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, R_L=10\Omega, R_{GEN}=3\Omega$		4.1	5.3	ns
Turn-On Rise Time	t_r			2.1		
Turn-Off DelayTime	$t_{d(\text{off})}$			15		
Turn-Off Fall Time	t_f			2.1		
Body Diode Reverse Recovery Time	t_{rr}	$I_F= 3\text{A}, dI/dt= 100\text{A}/\mu\text{s}$		23.4	29	nC
Body Diode Reverse Recovery Charge	Q_{rr}			23.2		
Maximum Body-Diode Continuous Current	I_S				2.5	A
Diode Forward Voltage	V_{SD}	$I_S=1\text{A}, V_{GS}=0\text{V}$			1	V

Note. The static characteristics in Figures 1 to 6 are obtained using <300us pulses, duty cycle 0.5% max.

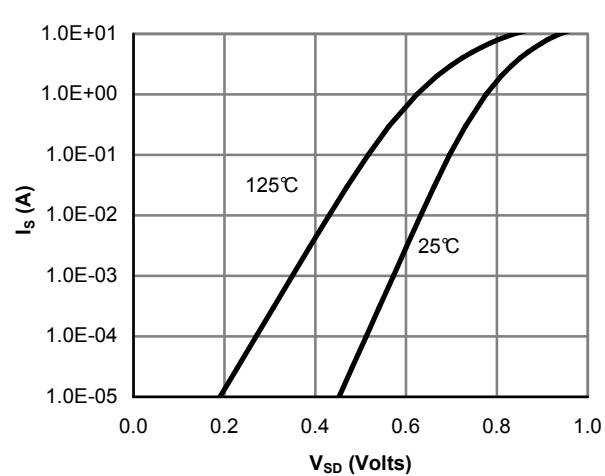
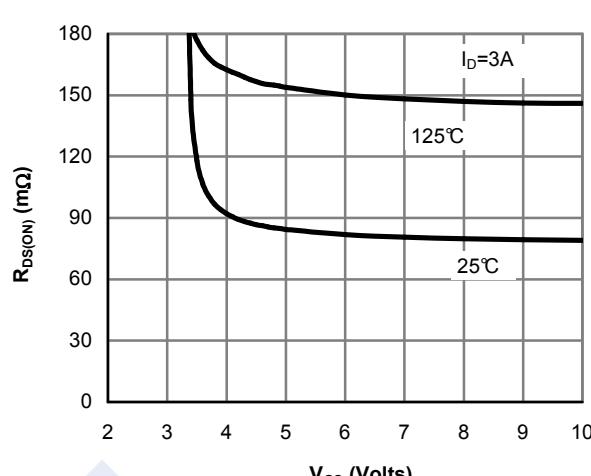
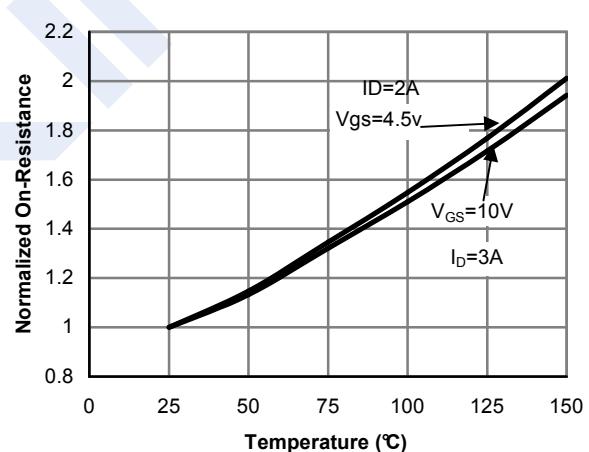
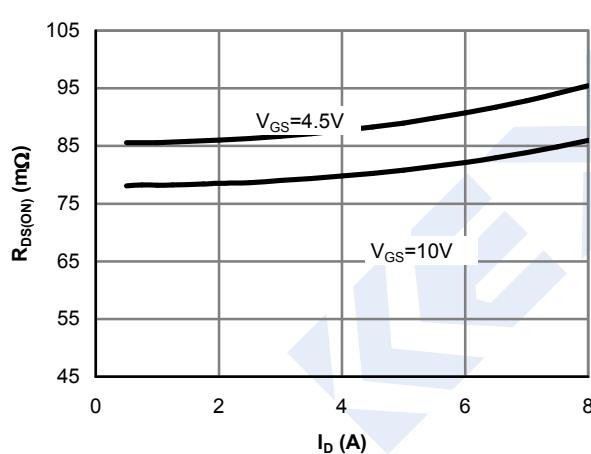
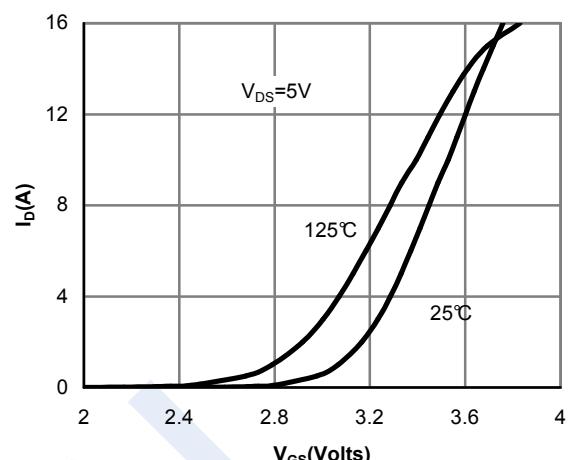
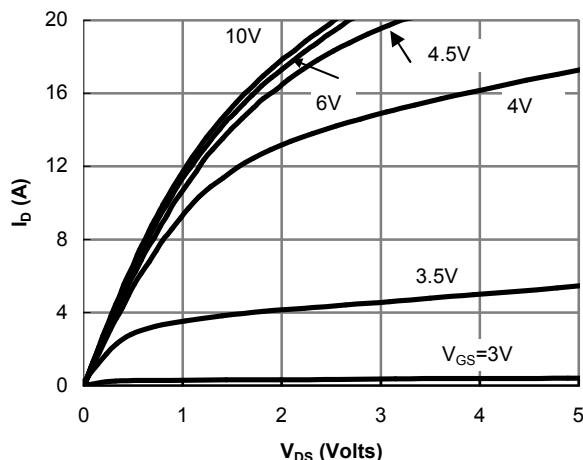
■ Marking

Marking	4852 KA****
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Dual N-Channel MOSFET

AO4852 (KO4852)

■ Typical Characteristics



Dual N-Channel MOSFET

AO4852 (KO4852)

■ Typical Characteristics

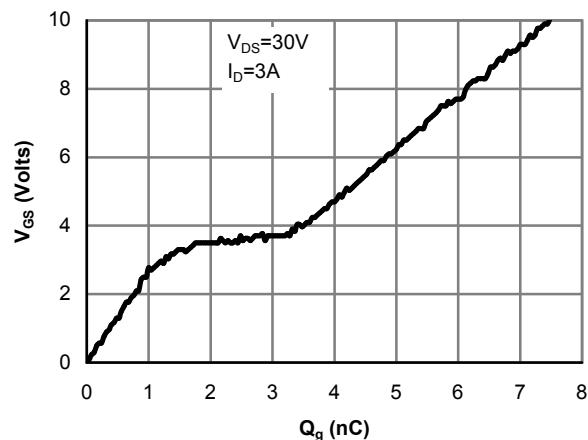


Figure 7: Gate-Charge Characteristics

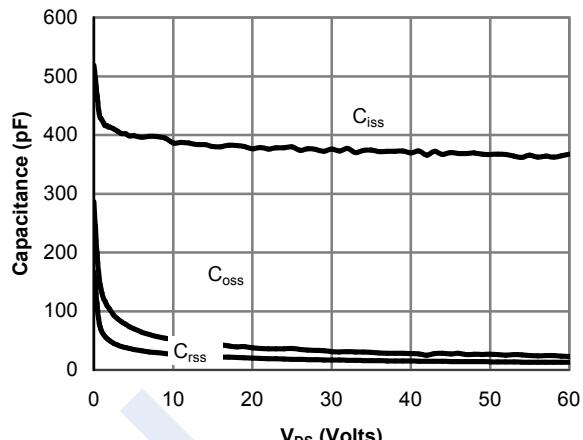


Figure 8: Capacitance Characteristics

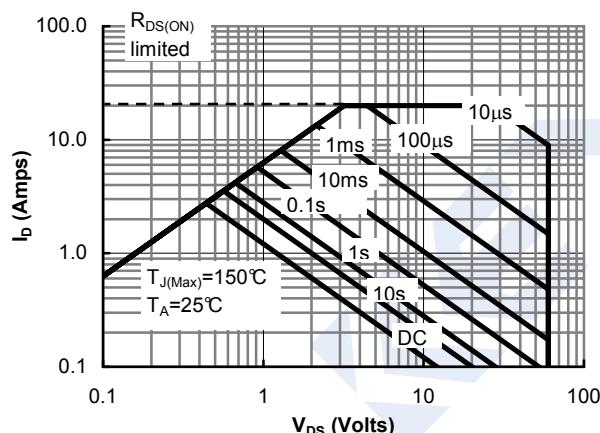


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

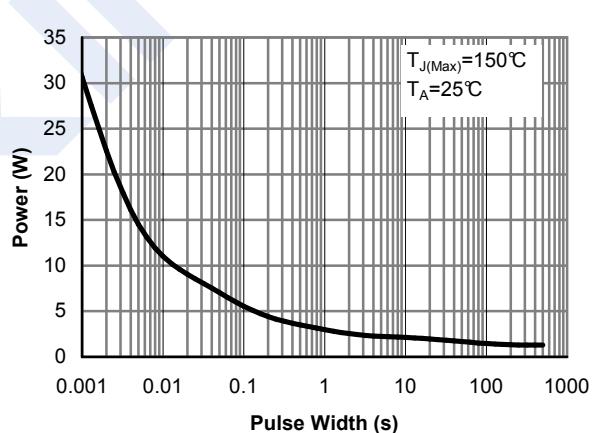


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

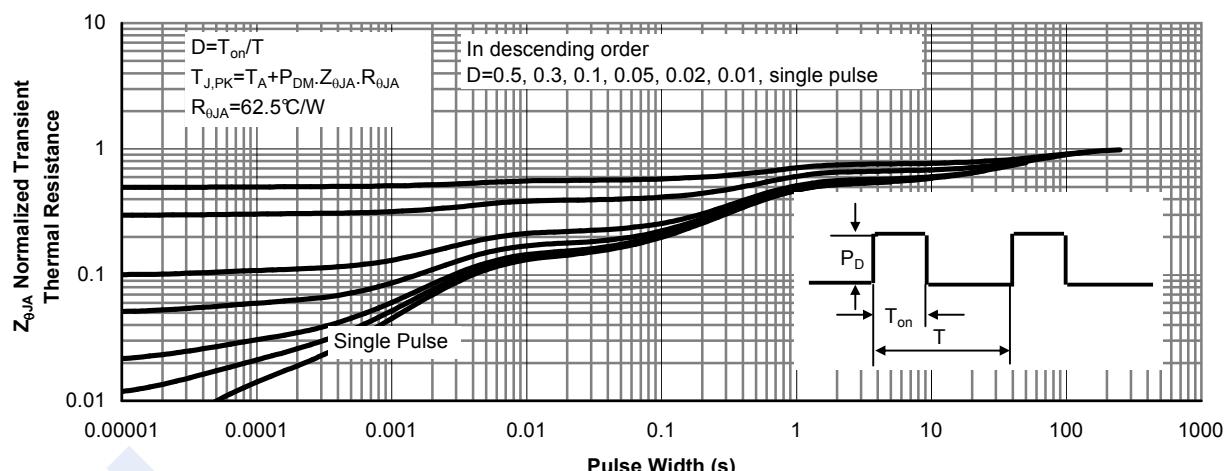


Figure 11: Normalized Maximum Transient Thermal Impedance